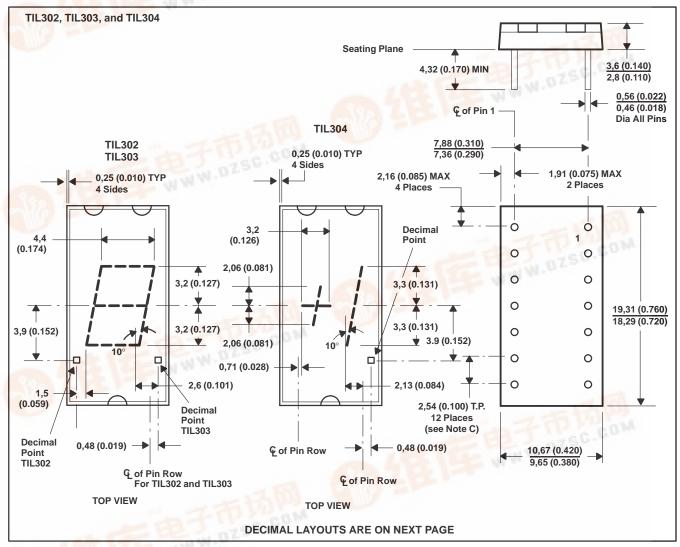
#### ,**T4L302急日送3**03, TIL304 查询TIL304供应商 捷多邦. 专业PCB打样工厂 NUMERIC DISPLAYS SOES010A, APRIL 1971 - REVISED DECEMBER 1993

- **Red Solid-State Display**
- 6,9-mm (0.270-Inch) Character Height ē
- e **High Luminous Intensity**
- Low Power Requirements
- Each Unit Visually Checked for Uniformity of Elements

- Sign, Overflow, and Left or Right Decimal Capabilities
- Wide Viewing Angle
- **Compatible With Most TTL and DTL** WWW.DZSC Circuits

## mechanical data

These assemblies consist of display chips mounted on a header with molded plastic body. Multiple displays may be mounted on 11,43-mm (0.450-inch) centers.



NOTES: A. All linear dimensions are in millimeters and parenthetically in inches.

B. Centerlines of character segments are shown as dashed lines. Associated dimensions are nominal.

C. The true-position pin spacing is 2,54 mm (0.100 inch) between centerlines. Each centerline is located within 0,26 mm (0.010 inch) of its true longitudinal position relative to pins 1 and 11.

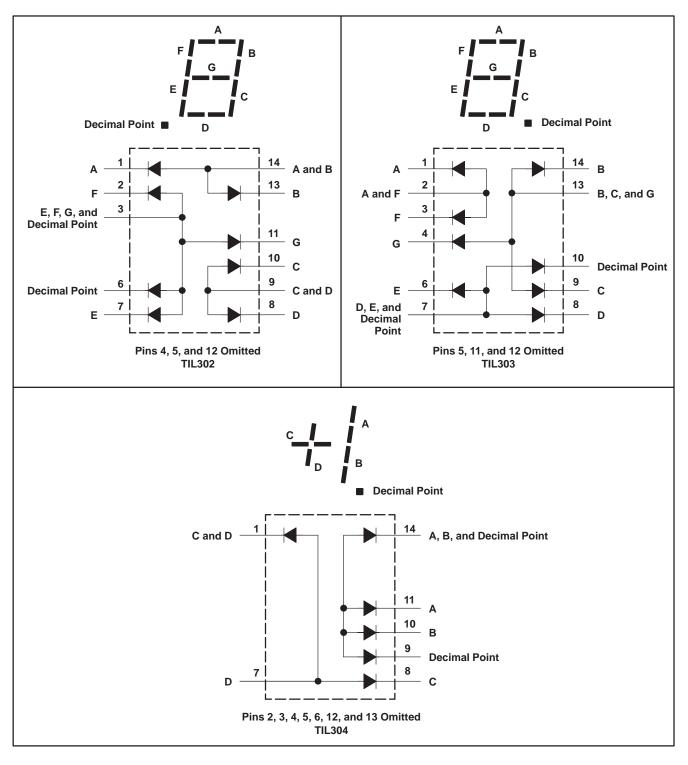


RCOUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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## pin layouts





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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

<b>a</b> 1	Each segment 6 V
D	Decimal point 3 V
Peak forward current, each segment or decimal p	point (see Note 1) 200 mA
Continuous forward current: Each segment or de	ecimal point 30 mA
Total for TIL302, TIL	_303 240 mA
Total for TIL304	150 mA
Operating free-air temperature range, TA	0°C to 70°C
Storage temperature range	−25°C to 85°C

NOTE 1: This value applies for PRR  $\ge$  60 Hz, duty cycle  $\le$  10%.

## operating characteristics of each segment at 25°C free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Ι <sub>V</sub>	Luminous intensity (see Note 2)		100	275		μcd
λp	Wavelength at peak emission	IF = 20 mA		660		nm
Δλ	Spectral bandwidth	F = 20  mA		20		nm
٧F	Static forward voltage		3	3.4	3.8	V
αVF	Average temperature coefficient of static forward voltage	$I_F = 20 \text{ mA},$ $T_A = 0^{\circ}C \text{ to } 70^{\circ}C$		-2.7		mV/°C
I <sub>R</sub>	Static reverse current	V <sub>R</sub> = 6 V			100	μA
С	Anode-to-cathode capacitance	$V_R = 0$ , f = 1 MHz		85		pF

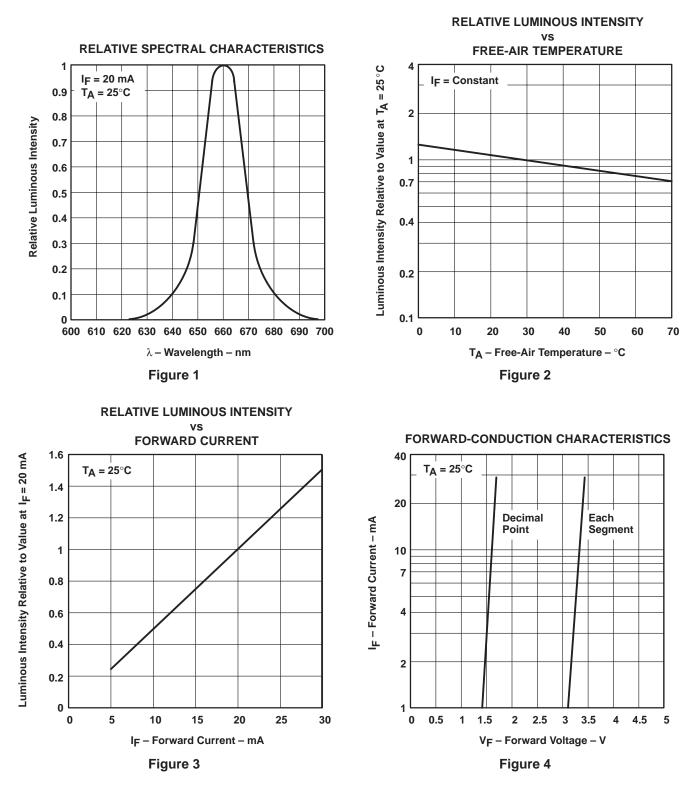
## operating characteristics of decimal point at 25°C free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Ι <sub>V</sub>	Luminous intensity (see Note 2)		40	110		μcd
λp	Wavelength at peak emission	IF = 20 mA		660		nm
Δλ	Spectral bandwidth	1F = 20 MA		20		nm
٧F	Static forward voltage		1.5	1.65	2	V
αVF	Average temperature coefficient of static forward voltage	$I_F = 20 \text{ mA},$ $T_A = 0^{\circ}\text{C} \text{ to } 70^{\circ}\text{C}$		-1.4		mV/°C
I <sub>R</sub>	Static reverse current	V <sub>R</sub> = 3 V			100	μA
С	Anode-to-cathode capacitance	$V_R = 0$ , $f = 1 MHz$		120		pF

NOTE 2: Luminous intensity is measured with a light sensor and filter combination that approximates the CIE (International Commission on Illumination) eye-response curve.



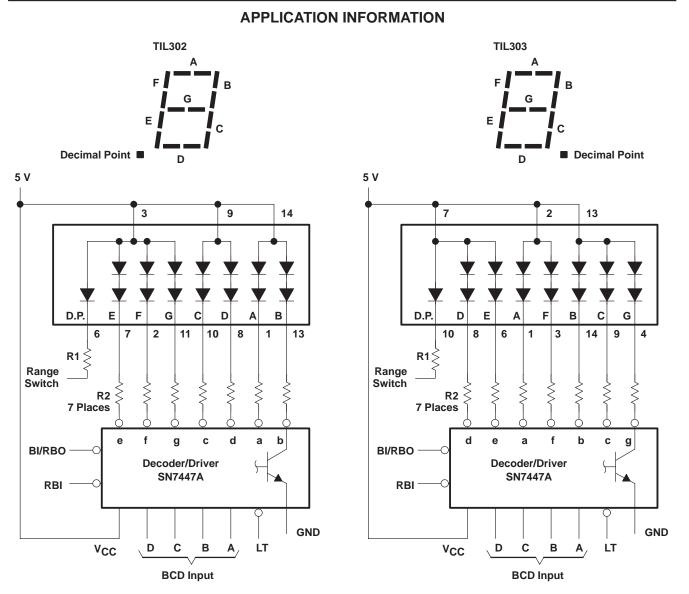
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## **TYPICAL CHARACTERISTICS**



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NOTE A: R1 and R2 are selected for desired brightness.



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						F	SN7447A	.E							
DECIMAL OR			INP	UTS				SEGMENTS							NOTE
FUNCTION	LT	RBI	D	С	В	Α	BI/RBO <sup>†</sup>	а	b	с	d	е	f	g	NOTE
0	Н	Н	L	L	L	L	Н	ON	ON	ON	ON	ON	ON	OFF	1
1	н	Х	L	L	L	Н	Н	OFF	ON	ON	OFF	OFF	OFF	OFF	1
2	н	Х	L	L	Н	L	Н	ON	ON	OFF	ON	ON	OFF	ON	1
3	н	Х	L	L	Н	Н	Н	ON	ON	ON	ON	OFF	OFF	ON	1
4	н	Х	L	Н	L	L	Н	OFF	ON	ON	OFF	OFF	ON	ON	1
5	н	Х	L	Н	L	Н	Н	ON	OFF	ON	ON	OFF	ON	ON	1
6	н	Х	L	Н	Н	L	Н	OFF	OFF	ON	ON	ON	ON	ON	1
7	н	Х	L	Н	Н	Н	Н	ON	ON	ON	OFF	OFF	OFF	OFF	1
8	н	Х	н	L	L	L	Н	ON	ON	ON	ON	ON	ON	ON	1
9	н	Х	н	L	L	Н	Н	ON	ON	ON	OFF	OFF	ON	ON	1
10	н	Х	н	L	Н	L	Н	OFF	OFF	OFF	ON	ON	OFF	ON	1
11	н	Х	н	L	Н	Н	Н	OFF	OFF	ON	ON	OFF	OFF	ON	1
12	н	Х	н	Н	L	L	Н	OFF	ON	OFF	OFF	OFF	ON	ON	1
13	н	Х	н	Н	L	Н	Н	ON	OFF	OFF	ON	OFF	ON	ON	1
14	н	Х	н	Н	Н	L	Н	OFF	OFF	OFF	ON	ON	ON	ON	1
15	Н	Х	Н	Н	Н	Н	Н	OFF	OFF	OFF	OFF	OFF	OFF	OFF	1
BI	Х	Х	Х	Х	Х	Х	L	OFF	OFF	OFF	OFF	OFF	OFF	OFF	2
RBI	н	L	L	L	L	L	L	OFF	OFF	OFF	OFF	OFF	OFF	OFF	3
LT	L	Х	Х	Х	Х	Х	Н	ON	ON	ON	ON	ON	ON	ON	4

## APPLICATION INFORMATION

# FUNCTION TABLE

H = high level (logic 1 in positive logic), L = low level (logic 0 in positive logic), X = irrelevant

<sup>†</sup> BI/RBO is a wire-AND logic serving as a blanking input (BI) and/or ripple-blanking output (RBO).

- NOTES: 1. The blanking input (BI) must be open or held at a high logic level when output functions 0 through 15 are desired. The ripple-blanking input (RBI) must be open or high if blanking of a decimal zero is not desired.
  - 2. When a low logic level is applied directly to the blanking input (BI), all segment outputs are off regardless of any other input.
  - 3. When the ripple-blanking input (RBI) and inputs A, B, C, and D are at a low logic level with the lamp-test input (LT) high, all segment outputs are off and the ripple-blanking output (RBO) of the decoder goes to a low level (response condition).
  - 4. When the blanking input/ripple-blanking output (BI/RBO) is open or held high and a low is applied to the lamp-test input (LT), all segments are illuminated.

	0 0 0										 [				
0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
NUMERICAL DESIGNATIONS RESULTANT DISPLAYS															



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